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	Application No.	Applicant(s)	
Notice of Allowability	10/798,013	SASAKI, HIROSHI	
	Examiner	Art Unit	
	Que T. Le	2878	
The MAILING DATE of this communication app.  All claims being allowable, PROSECUTION ON THE MERITS I herewith (or previously mailed), a Notice of Allowance (PTOL-8: NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT of the Office or upon petition by the applicant. See 37 CFR 1.3	S (OR REMAINS) CLOSED in this ap 5) or other appropriate communication RIGHTS. This application is subject t	plication. If not include n will be mailed in due o	d course. THIS
1. This communication is responsive to			
2. The allowed claim(s) is/are <u>1-38</u> .			
<ul> <li>3. Acknowledgment is made of a claim for foreign priority and an an</li></ul>	ve been received.  ve been received in Application No  documents have been received in this  " of this communication to file a reply	national stage applicati	
4. A SUBSTITUTE OATH OR DECLARATION must be sub INFORMAL PATENT APPLICATION (PTO-152) which gi			OTICE OF
<ol> <li>CORRECTED DRAWINGS ( as "replacement sheets") me</li> <li>(a) including changes required by the Notice of Draftspe</li> <li>1) hereto or 2) to Paper No./Mail Date</li> <li>(b) including changes required by the attached Examine Paper No./Mail Date</li> <li>Identifying indicia such as the application number (see 37 CFR each sheet. Replacement sheet(s) should be labeled as such in</li> </ol>	erson's Patent Drawing Review(PTO- —· er's Amendment / Comment or in the C  1.84(c)) should be written on the drawi	Office action of ngs in the front (not the	back) of
6. DEPOSIT OF and/or INFORMATION about the department attached Examiner's comment regarding REQUIREMENT			ote the
<ul> <li>Attachment(s)</li> <li>1. ☑ Notice of References Cited (PTO-892)</li> <li>2. ☐ Notice of Draftperson's Patent Drawing Review (PTO-948)</li> <li>3. ☑ Information Disclosure Statements (PTO-1449 or PTO/SB Paper No./Mail Date</li></ul>	Paper No./Mail Da 3/08), 7. ⊠ Examiner's Amenda	t (PTO-413), tement/Comment ent of Reasons for Allow	wance
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An examiner's amendment to the record appears below. Should the changes and/or additions be unacceptable to applicant, an amendment may be filed as provided by 37 CFR 1.312. To ensure consideration of such an amendment, it MUST be submitted no later than the payment of the issue fee.

The <u>title of the invention</u> has been changed to: "Scanning laser microscope having a spectrum image positional correction".

The following is an examiner's statement of reasons for allowance: The prior art fails to teach a scanning laser microscope, among other features, comprising: a laser source; a dispersive element disperses light emitted from a sample and makes spectrum; an image formation element forming an image of spectrum made by the dispersive element; a photodetector for detecting light in each wavelength band being arranged in the spectral direction; at least one optical element selectively arranged between the sample and the dispersive element; and a correction portion for correcting a positional relationship of a position of the spectrum image which is displaced due to a change caused by switching the optical element. The prior art also fails to teach a scanning microscope, among other features, comprising: a laser source; a plurality of spectral beam splitters dividing emitted light from a sample into respective light in accordance with a plurality of wavelength band when irradiating the sample with the laser beam; a plurality of dispersive elements disperses to spectrums the respective light according to the wavelength band divided by the splitters; a plurality of image

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formation elements each forms an image of the spectrums; a plurality of wavelength band extraction portions extract respective light in at least one wavelength band from the respective spectrums; a plurality of photodetectors; and a correction portion having stored correction quantities corresponding to each of the displacements of the spectrum image position relative to each of the beam splitters to control the rotation of the dispersive elements in accordance with the correction quantity relative to the spectral beam splitter when switched to this spectral beam splitter, and to correct the spectrum image positions relative to the wavelength band extraction portions.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

The prior art made of record and not relied upon is considered pertinent to applicant's disclosure.

I) Yokoi 6,396,053 discloses a scanning microscope system having an array of light deflecting microelements.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Que T. Le whose telephone number is (571) 272-2438.

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If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, David P. Porta, can be reached on (571) 272-2444. The fax phone number for the organization where this application or proceeding is assigned is (703) 872-9306.

Any inquiry of a general nature or relating to the status of this application or proceeding should be directed to the receptionist whose telephone number is (703) 308-0956.

Que T. Le

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**Primary Examiner**